

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination AVADHANAM ET AL.	
			Examiner Srirama Channavajjala	Art Unit 2166	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,438,562	08-2002	Gupta et al.	707/201
*	B	US-5,842,208	11-1998	Blank et al.	707/7
*	C	US-6,175,835	01-2001	Shadmon, Moshe	707/102
*	D	US-2004/0111410	06-2004	Burgoon et al.	707/004
*	E	US-6,169,983	01-2001	Chaudhuri et al.	707/2
*	F	US-6,311,181	10-2001	Lee et al.	707/5
*	G	US-2003/0204515	10-2003	Shadmon et al.	707/100
*	H	US-6,728,709	04-2004	Plasek et al.	707/8
*	I	US-2002/0120598	08-2002	Shadmon et al.	707/1
*	J	US-6,778,977	08-2004	Avadhanam et al.	707/2
*	K	US-2005/0027744	02-2005	Avadhanam et al.	707/104.1
*	L	US-2005/0198019	09-2005	Cunningham et al.	707/003
*	M	US-6,714,938	03-2004	Avadhanam et al.	707/102

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	GB2207264	01-1989	UK	Shunichiro Nakamura et al	15/40
	O	WO99/33002	07-1999	PCT	NG Tony et al.	17/30
	P	EP 1548583	06-2005	European	Nishida,Tsuyoshi	9/445
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Shengli Wu et al. "histogram method for size estimation of query result", IEEE international conference on intelligent processing systems, 1997, pp 1594-1598
	V	Viswanath Poosala et al. "selectivity estimation without the attribute value independence assumption", proceedings of the 23rd VLDB conference, 1997, pp 486-495
	W	Yannis E Ioannidis et al. "histrogram-based approximatuon of set-valued query answers", proceedings of the 25th VLDB conference, pp 174-185
	X	Xiao-jing et al. "self-learning histograms for changing workloads", proceedings of the 9th international database engineering & application symposium (IDEAS'05), IEEE 2005,

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.